

### SuperB EMC Electronics

La Biodola SuperB Workshop May 28 June 2, 2011

Valerio Bocci INFN Roma

EMC electronics: INFN Roma, INFN Perugia



### SuperB EMC





# 25 crystals tower readout electronics





### Very Front End Board

EMC VFE Board
S CSP Channels
Enable to mount: Cremat,
Hamamatsu,
Home Made CSP
HV distribution





# Very Front End Board

(PCB layout D. Ruggieri, A.Papi)

•EMC VFE Board

•4 Layers

•5 CSP Channels

•Enable to mount:

Cremat, Hamamatsu, Home Made CSP

•HV distribution

Mounted on crystals

•Interface with EMC range Board





# Three Type of CSP under evaluation

Cremat, Inc.

CR-110 rev. 2

Cremat 1.4 V/pC







WE can change Rf constant.



### Babar Energy resolution Energy Resolution



LNF SuperB Workshop April 4- 7, 2011 Valerio Bocci

# **Energy Resolution SuperB**





### EMC Ranges shaper board test beam settings





### **EMC** Range Board

(PCB layout R.Lunadei,G.Chiodi)

EMC Range Board
8 Layers VME size
5 Channels Analog Differential input
5 Channles Analog Differential output
1 Main clock input
Long line I2c control input
Range info analog coded
Lvds output for Range bit





# VFE inside the copper Box

#### (INFN Perugia, INFN Roma)





Cabling by M.Bizzarri







### As we know the noise spectrum depends from the shaping time we do not find any noise source with an heavy contribution.



More noise

### Power Spectrum 500 ns Shaper



This is the shaping time used in LNF beam test

### Power Spectrum 200 ns Shaper



### Power Spectrum 100 ns Shaper



#### This is the shaping time used during the CERN and BTF test beam

We integrate the noise spectrum and we have evaluated the noise level in Veff

- 100ns -> 745 uVeff(0.5-10.5 MHz)
- 200 ns -> 565 uVeff (0.5-3.5 MHz)
- 500 ns -> 418 uVeff (0.1-2.1 MHz )

Mev 600 uv High Gain during CERN test Beam
 Mev 180 uv Low Gain during CERN test Beam



### EMC Fast Trigger Path and Slow Energy Path



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### EMC Forward tentative of Implementation



# May 2011 LNF BTF Beam Test



From Elisa Manoni Presentation

O Fit function :  $p_0/\sqrt{E(GeV)} \oplus p_1/E(GeV) \oplus p_2$ 



#### second order problems found during the test beam





### **Xtalk Matrix measuraments**

(A.Papi L.Recchia)

	2.2%	2.0%	1.7%	1.7%	<b>←</b> Ch0
	 2.2%	2.0%	2.0%	2.0%	
	1.2%	1.2%	1.1%	1.0%	
	 0.5%	0.5%	0.5%	0.5%	
	 0.0 /0				
Ch24	2.2%	2.0%	2.4%	1.7%	

Ch3= Ch3(real) + 2.2% of Ch4



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### VFE Board Xtalk Source and target



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# Final Xtalk solution

(by Luigi Recchia)







### Preliminary ruffle estimation of FE Power

- 0.5 W/Ch CSP
- 1 W/ch Shaping switching
- <1 W/ch Adc including buffers and logic</li>
- Tot 2 W/Ch
- ruffle FE forward Barrel + Forward → 20 Kwatt

# Digital part of the Front End

- We are interested to explore the possibility to use Xilinx FPGA in the Front End
- The use of such flexible device have positive impact of the architecture
- A qualification in short time is necessary
- We have explored and used this approach some years ago:

Radiation Test and Application of FPGAs in the Atlas

Level 1 Trigger,

V. Bocci at al, 7° Workshop on Electronics for LHC Experiments, Stockholm, Sweden,

September 2001

bttp://edoweb.com.eb/moor

http://cdsweb.cern.ch/record/529388/files/p137.pdf

# Conclusions

- We replicate the results from the CERN test beam
- The Better conditions of the Environment permits to discover second order effects not cleary visible during test CERN
- About the architecture and design of digital part of the front end the possibility of use of Xilinx FPGA can have a strong positive impact.